

U.S. DEPARTMENT OF COMMERCE
 PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.
00684.102862

APPLICATION NO.
To be assigned

LIST OF REFERENCES CITED BY APPLICANT(S)
 (Use several sheets if necessary)

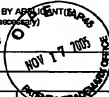
APPLICANTS
HIDEKI YOSHINAGA, ET AL.

FILING DATE
October 11, 2005

GROUP
To be assigned

Submitted to the PTO: November 17, 2005

U.S. PATENT DOCUMENTS



EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,489,899	12/2002	Ely, et al.	341	20	
	6,445,489	09/2002	Jacobson, et al.	359	296	
	5,444,190	08/1995	Yamanami, et al.	178	18	

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO OR ABSTRACT
WO 92/16368	10/1992	PCT			
0 461 614	12/1991	Europe			
0 511 406	11/1992	Europe			

OTHER DOCUMENT(S) (including Author, Title, Date, Pertinent Pages, Etc.)

	L. Ferraris, "EMI Shielding-Common Problems and Containment Strategies", Electromagnetic Compatibility Proceedings, International Symposium on Beijing, China, pp. 88-89 (May 21, 1997).
	V.A. Soglasnova, et al., "Amplitude and Phase Characteristics of Metal Meshes-The Elements of Submillimeter Interference Filters", International Journal of Infrared and Millimeter Waves, Vol. 14, No. 1, pp. 155-168 (January 1993).
	W. Jing, et al., "The Calculating and Analysis of Shielding Effectiveness of Metal Meshes in Transient Electromagnetic Interference", Environment Electromagnetics, Proceedings, Asia-Pacific Conference of Hangzhou, pp. 379-385 (November 4-7, 2003).

EXAMINER /Yuk Chow/

DATE CONSIDERED 01/27/2011

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Sheet 1 of 1

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